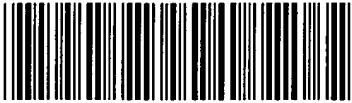
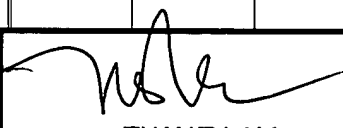



Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,673	LEE ET AL.	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
327		589			327	306	331	332	
INTERNATIONAL CLASSIFICATION					361	91.1	18	98	
H	0	2	M	3/07					
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				/					
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Hiep Nguyen (Assistant Examiner) (Date)		 TUAN T. LAM PRIMARY EXAMINER (Primary Examiner)	Total Claims Allowed: 13	
 (Legal Instruments Examiner) (Date)			O.G. Print Claim(s) 1	O.G. Print Fig. 2

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
1	①						
2	2						
3	3						
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